Information Only Service Note

Supersedes: NONE

Keysight i3070 Series 5 In-Circuit Test System E9905E, E9905EL, E9903E, E9902E, E9901E, E9901EL E9988EL, E9988E, E9986E (inline)

Serial Numbers: ALL

Manufacturing ID Number: NA

The Problem - Specification revise i3070 Series 5 for ASRU Revision N DC Voltage Detection

Parts Required:

P/N Description Qty.

NONE

ADMINISTRATIVE INFORMATION

[[]] Calibration Required PRODUCT LINE: PL80
X Calibration NOT Required AUTHOR: Wee Sheng

ADDITIONAL INFORMATION:



Situation:

Analog Stimulus Response Unit (ASRU) Revision N was shipped with i3070 Series 5 since year 2009. Over time, various engineering change orders (ECOs) have been implemented to address obsolesces components on the card.

Consequently, the test limits for DC voltage detection were adjusted to align with the hardware's behavior in the software version 09.01p, which was released in 2017. However, the Normal accuracy specification for DC Voltage Detection in ASRU Revision N in i3070 Series 5 was not updated to reflect these changes.

Solution/Action:

Based on the software released in 2017 version 09.01p, the correct specification for the Normal accuracy of DC Voltage Detection of ASRU Revision N is revised as per below:

Accuracy ¹	Normal	± (0.02% of reading + 0.05% of range + 300 μV)
		\pm (0.1% of reading + 0.2% of range + 600 μ V) for ASRU-N
	Line Rejection	± (0.02% of reading + 0.05% of range + 300 μV)

- 1. Add 0.12% of reading for attenuated ranges.
 - For users who have used i3070 software version 09.01p and later have already been using the corrected specification. Therefore, there is no risk to your product testing, and no further action is necessary.
 - For users who are using i3070 software versions prior to 09.01p, you may experience failures reported for ASRU Revision N units received recently, primarily due to the test limits in the earlier software. It is recommended that you update to the latest software version for the latest revised limits. There is no risk to the quality of your product testing.

Revision History:

Date	Service Note Revision	Author	Reason for Change	
20 Sep 2023	01	Wee Sheng	As Published	